## Application/Control No. Applicant(s)/Patent Under Reexamination 10/789,587 YOON ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Sam Bhattacharya 2617 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY \* US-5,987,320 11-1999 Bobick, David A. 455/423 Α US-В US-С US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-Ľ US-М **FOREIGN PATENT DOCUMENTS** Document Number Country Code-Number-Kind Code Date Country Name Classification MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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